TOSHIBA Field Effect Transistor Silicon N Channel MOS Type

SSM3K101TU

High Speed Switching Applications

• 1.8V drive

• Low on-resistance: $R_{on} = 230m\Omega \text{ (max) (@V_{GS} = 1.8 V)}$

 $R_{on} = 138m\Omega \text{ (max) } (@V_{GS} = 2.5 \text{ V})$

 $R_{on} = 103m\Omega \text{ (max) } (@V_{GS} = 4.0 \text{ V})$

• Lead(Pb)-free

Maximum Ratings (Ta = 25°C)

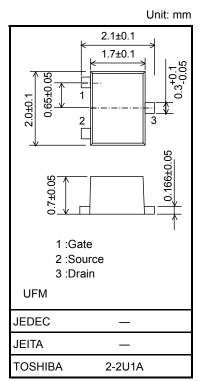
Characteristic		Symbol	Rating	Unit	
Drain-Source voltage		V_{DS}	20	V	
Gate-Source voltage		V_{GSS}	± 12	٧	
Drain current	DC	I _D	2.2	А	
	Pulse	I _{DP}	4.4		
Drain power dissipation		P _{D (Note1)}	800	mW	
Drain power dissipation	nam power dissipation		500		
Channel temperature		T _{ch}	150	°C	
Storage temperature range		T _{stg}	-55~150	°C	

Note1: Mounted on ceramic board.

(25.4 mm \times 25.4 mm \times 0.8 mm, Cu Pad: 645 mm²)

Note2: Mounted on FR4 board.

 $(25.4 \text{ mm} \times 25.4 \text{ mm} \times 1.6 \text{ mm}, \text{ Cu Pad: } 645 \text{ mm}^2)$



Weight: 6.6 mg (typ.)

Electrical Characteristics (Ta = 25°C)

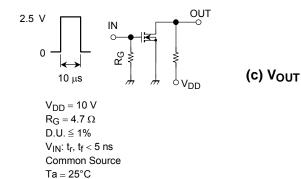
Charact	teristic	Symbol	Test Conditions		Min	Тур.	Max	Unit	
Drain-Source breakdown voltage		V (BR) DSS	$I_D = 1 \text{ mA}, V_{GS} = 0$		20	_	_	V	
		V (BR) DSX	$I_D = 1 \text{ mA}, V_{GS} = -12 \text{ V}$		12	_	_		
Drain cut-off currer	nt	I _{DSS}	V _{DS} = 20 V, V _{GS} = 0		_	_	1	μА	
Gate leakage curre	ent	I _{GSS}	$V_{GS} = \pm 12V, V_{DS} = 0$		_	_	±1	μА	
Gate threshold volt	age	V _{th}	$V_{DS} = 3 \text{ V}, I_{D} = 1 \text{ mA}$		0.4	_	1.0	V	
Forward transfer ad	dmittance	Y _{fs}	$V_{DS} = 3 \text{ V}, I_{D} = 1.0 \text{ A}$	(Note3)	2.7	4.5		S	
Drain-Source on-resistance		R _{DS (ON)}	$I_D = 1.0 \text{ A}, V_{GS} = 4.0 \text{ V}$	(Note3)	_	85	103	mΩ	
			$I_D = 0.5 \text{ A}, V_{GS} = 2.5 \text{ V}$	(Note3)	_	105	138		
			$I_D = 0.2 \text{ A}, V_{GS} = 1.8 \text{ V}$	(Note3)	_	140	230		
Input capacitance		C _{iss}	V _{DS} = 10 V, V _{GS} = 0, f = 1 MHz		_	125		pF	
Output capacitance		C _{oss}	V _{DS} = 10 V, V _{GS} = 0, f = 1 MHz		_	42		pF	
Reverse transfer capacitance		C _{rss}	V _{DS} = 10 V, V _{GS} = 0, f = 1 MHz		_	17	_	pF	
Switching time	Turn-on time	t _{on}	$V_{DD} = 10 \text{ V}, I_D = 0.75 \text{ A},$		_	14	_	ns	
	Turn-off time	t _{off}	$V_{GS} = 0~2.5 \text{ V}, R_G = 4.7 \Omega$		_	20	_		
Drain-Source forward voltage		V _{DSF}	$I_D = -2.2A, V_{GS} = 0 V$	(Note3)	_	-0.85	-1.2	V	

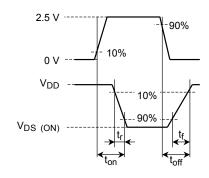
Note3: Pulse test

Switching Time Test Circuit

(a) Test Circuit

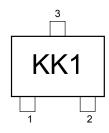
(b) V_{IN}

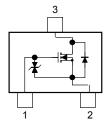




Marking

Equivalent Circuit (top view)





Precaution

 V_{th} can be expressed as the voltage between gate and source when the low operating current value is I_D =1mA for this product. For normal switching operation, V_{GS} (on) requires a higher voltage than V_{th} , and V_{GS} (off) requires a lower voltage than V_{th} .

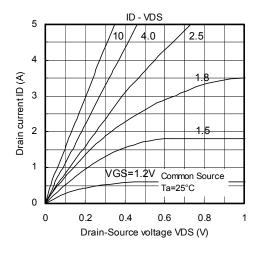
(The relationship can be established as follows: $V_{GS (off)} < V_{th} < V_{GS (on)}$)

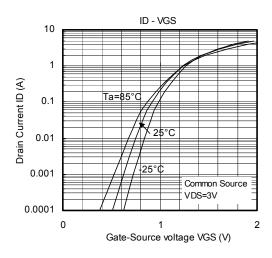
Take this into consideration when using the device.

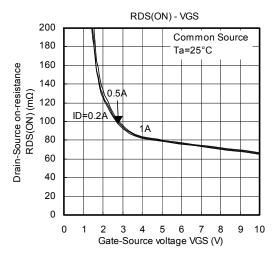
The recommended VGS voltage for turning on this product is 1.8 V or higher.

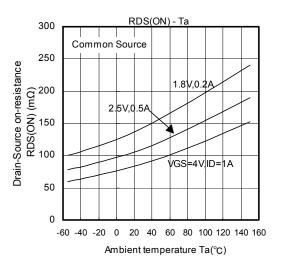
Handling Precaution

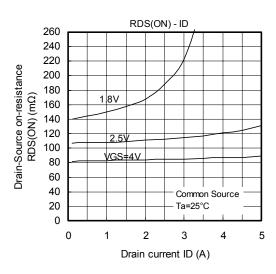
When handling individual devices which are not yet mounted on a circuit board, be sure that the environment is protected against electrostatic discharge. Operators should wear anti-static clothing, and containers and other objects that come into direct contact with devices should be made of anti-static materials.

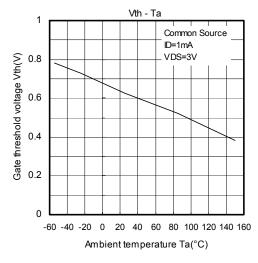


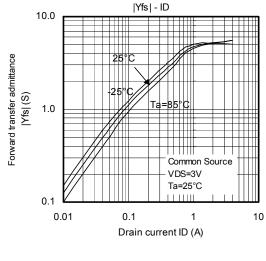


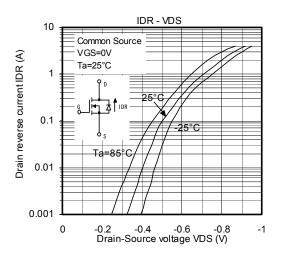


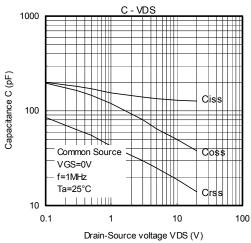


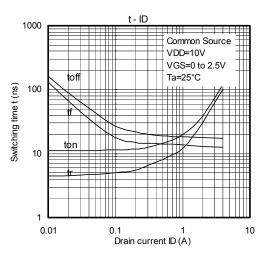


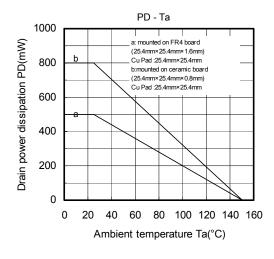


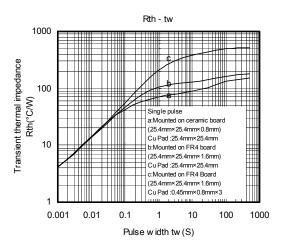












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